Preliminary Figures Request: Measurement of W^+/W^- cross ratio at RHIC

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Efficiency



Efficiency



Results





 Additional source of systematic uncertainty from charge dependence in the efficiency ~6%.











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Measurements of $\overline{d}/\overline{u}$ asymmetry



- The \bar{d}/\bar{u} flavor asymmetry
 - Predominantly measured via Drell-Yan, such as NuSea/E866 and SeaQuest/E906.
 - Tension between measurements around the valence region.
- W production at STAR/RHIC
 - LO production sensitive to \overline{d} (W^+) and \overline{u} (W^-).
 - The cross-section ratio $\sigma_{W^+}/\sigma_{W^-}$ can be used to probe \bar{d}/\bar{u} ;

$$R_W = \frac{\sigma_{W^+}}{\sigma_{W^-}} \approx \frac{u(x_1) \,\bar{d}(x_2) + u(x_2) \,\bar{d}(x_1)}{\bar{u}(x_1) \,d(x_2) + \bar{u}(x_2) \,d(x_1)}$$

- Naturally provides a large momentum scale, $Q^2 \approx M_W^2$.
- Sensitive to \bar{d}/\bar{u} in the region 0.1 < x < 0.3 in the STAR mid-rapidity ($|\eta| < 1$).
- Kinematic reach further stretched to 0.06 < x < 0.4 with Endcap EM Calorimeter (EEMC).
- Characteristically produces final state v.
- Isolated high p_T electron.



- Dataset
 - Dataset: st_W
 - Year: 2017 (P20ic)
 - Production tags: pp500_production_2017
 - Triggers used:
 - L2BW (570202)
 - L2EW (570206)
 - Embedding request id: 20201502
- Measurement
 - $R_W (= \sigma^{W^+ \to e\nu} / \sigma^{W^- \to e\nu})$ measurement in the endcap region $(1 < \eta < 1.5)$ by tagging the leptonic decay of $q\bar{q} \to W$.
 - In addition to the measurement in the barrel region.
 - <u>https://drupal.star.bnl.gov/STAR/blog/jaenam/run-17-measurement-ww-cross-</u> <u>section-ratio-rhic-preliminary-request</u>





Bad run list

18054071 18055034 18055046 18056014 18056016 18056035 18056036 18056087 18056088 18057091 18057107 18058011 18058012 18058016 18059024 18059056 18059062 18059063 18060106 18060107 18060110 18060112 18060114 18060116 18061033 18061090 18061092 18062040 18062043 18062053 18062054 18063029 18063033 18063068 18063087 18063093 18063094 18063095 18063096 18063097 18063098 18063099 18063101 18063117 18063118 18063119 18064004 18064014 18065029 18065030 18065045 18065050 18065070 18066016 18067073 18067074 18067075 18067080 18067092 18068019 18068020 18068026 18068027 18068028 18071078 18072004 18072007 18072018 18072055 18074025 18074028 18075001 18075010 18075090 18076006 18077003 18077008 18077014 18077039 18077040 18078066 18079035 18079038 18080016 18080017 18080025 18080028 18080032 18080046 18080047 18080049 18080052 18080053 18080061 18081008 18081011 18081012 18081016 18081019 18083041 18083053 18084014 18084050 18084051 18085002 18085009 18085016 18085043 18085050 18085058 18087008 18087037 18087038 18087040 18088039 18089005 18089056 18089057 18089058 18089059 18089062 18089064 18090019 18090023 18090058 18090059 18090065 18091004 18091008 18091018 18091025 18091026 18091027 18092001 18092003 18092004 18092005 18092014 18092022 18092025 18092026 18092029 18092030 18092031 18092032 18092033 18092035 18092036 18092038 18092056 18092076 18092087 18092099 18093005 18093007 18093026 18093032 18093051 18093068 18094002 18094003 18094005 18094006 18094009 18094011 18094012 18094015 18094016 18094019 18094021 18094029 18094032 18094033 18094035 18094036 18094037 18094061 18094066 18095016 18095017 18095018 18095019 18095053 18097002 18097004 18097006 18097011 18097057 18098013 18098034 18099005 18099042 18101022 18101029 18101033 18101034 18101035 18102024 18103019 18103050 18104021 18105001 18105039 18105043 18106010 18106036 18106042 18106055 18106067 18107029 18108011 18108017 18108018 18108019 18108024 18108036 18108038 18108055 18108056 18108058 18108081 18109002 18109004 18109006 18109011 18109013 18109018 18109031 18109035 18109053 18112012 18112036 18112037 18113030 18113042 18117021 18117030 18118018 18118022 18118038 18118040 18119018 18119019 18119021 18120049 18121008 18121009 18121014 18121017 18121022 18121023 18122019 18122039 18122040 18124010 18124024 18127073 18127075 18127079 18127081 18127090 18128003 18128004 18128035 18128055 18129010 18129012 18131094 18132031 18133001 18133053 18134006 18134043 18134044 18134045 18134046 18134053 18135001 18135019 18135020 18135032 18135053 18135055 18136012 18136013 18136017 18137028 18139044 18141007 18141013 18143003 18144008 18146031 18147007 18148007 18148021 18149061





Event selection

- Based on the previous publication (Phys.Rev.D 103 (2021) 1, 012001)
 - Relaxed tracking requirements due to limited TPC acceptance region.
 - Additional constraints provided from ESMD.

Criteria	Relevant quantities	Selection cut		
Trigger	Trigger	L2EW		
Vertex	Vertex Rank	> 0		
	Vertex z	z < 100 cm		
Track	N_{hits} = number of TPC hits	> 5		
	N_{hits}/N_{pos}	≥ 0.51		
	$R_{IN} = \text{inner most TPC radius}$	< 120 cm		
	R _{OUT}	> 70 cm		
	N_{ESMD} = number of ESMD strips signaled	> 20		
	$r_{ESMD} = \frac{\sum_{i=-3}^{+3} E_i^U + E_i^V}{\sum_{i=-20}^{+20} E_i^U + E_i^V}$	> 0.6		
Cluster	$E_T^{2 \times 2}$	> 16 GeV		
	$E_T^{2\times 2}/E_T^{4\times 4}$	> 0.97		
	R _{cluster-track}	< 10 cm		
e ^W tagging	$E_T^{2\times 2}/E_T^{\Delta R<0.7}$	> 0.88		
	$Q \times E_T / p_T$	$0.4 < Q \times E_T / p_T < 1.8$		
	sp _{T,bal}	> 20 GeV		
	$E_T = E_T^{2 \times 2}$	$25 \ GeV < E_T < 50 \ GeV$		

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Procedure

• In the W cross section ratio measurement, the ratio reduces to:

$$\frac{\sigma_{W^+}}{\sigma_{W^-}} = \frac{r_{charge}^-}{r_{charge}^+} \cdot \frac{\epsilon^-}{\epsilon^+} \cdot \frac{N_{obs}^+}{N_{obs}^-} = \frac{r_{charge}^-}{r_{charge}^+} \cdot \frac{\epsilon^-}{\epsilon^+} \cdot \frac{N_{sig}^+ - N_{bg}^+}{N_{sig}^- - N_{bg}^-}$$

• where ϵ represents the sum of the efficiencies of our selection process.

 $\epsilon = \epsilon_{trigger} \times \epsilon_{vertex} \times \epsilon_{tracking} \times \epsilon_{tagging}$

• N_{bg} represents the sum of all remaining background contributions.

 $N_{bg} = N_{W \to \tau \nu} + N_{Z \to ee} + N_{QCD} + N_{EEMC}$ (second EEMC background only for barrel measurements)

- $N_{W \to \tau \nu}$ and $N_{Z \to ee}$ are entirely determined from events from the embedding samples that pass the selection cuts.
- N_{QCD} represents the QCD background events that pass the selection cuts. Its shape is estimated by looking at the distribution of events with **low** r_{ESMD} (< 0.4) and normalize to match the discrepancy between data and background estimates in $sp_{T,bal}$ window $-8 < sp_{T,bal}/GeV < 14$.
- Finally, a correction factor is determined from data and MC to obtain the fraction of correctly assigned electron charge.

$$\frac{\bar{r_{charge}}}{r_{charge}^+} = \frac{N_{cor}^-/N_{obs}^-}{N_{cor}^+/N_{obs}^+}$$



Background description



- Background contributions
 - EW contributions $(Z \rightarrow ee, W \rightarrow \tau \nu_{\tau})$ are estimated with the embedding scaled to data luminosity
 - Data-driven QCD distribution is first obtained from the distribution with $r_{ESMD} < 0.4$. This is then scaled to match the discrepancy between data and the other background contributions in the region of $-8 \ GeV < sp_{T,bal} < 14 \ GeV$.
- Similar degree of agreement to Run 11+12+13 (backup)



Efficiency correction



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Efficiency correction (continued)



- The efficiency of *W* tagging in the endcap is evaluated within the region
 - $25 \ GeV < E_T < 50 \ GeV$
 - $1 < \eta < 1.5$
- No strong charge dependence has been found.
- The efficiency correction factor (ϵ^-/ϵ^+) has been found to be

$$\frac{\epsilon^{-}}{\epsilon^{+}} = \frac{N_{sig}^{-}/N_{gen}^{-}}{N_{sig}^{+}/N_{gen}^{+}} = \frac{0.75}{0.74} = 1.01$$

Charge correction



- Two different calculations have been ٠ tested for charge correction estimate.
- MC template (4-Gaus) ٠
 - $Q \times E_T / p_T$ distributions from the $W^$ and W^+ embedding samples are fitted to 2-Gaus function
 - The widths and means of these • Gaus's are used as template for the 4-Gaus fit to the data.
- Log-likelihood (2-Gaus) ٠
 - The charge distribution from data is directly fit to 2-Gaus function.
- Charge correction factor •

$$\left(\frac{r^{-}}{r^{+}}\right)_{4Gaus} = \frac{N_{cor}^{-}/N^{-}}{N_{cor}^{+}/N^{+}} = \frac{145.9/205}{180.2/214} = 0.96$$

$$\binom{r^{-}}{r^{+}}_{2Gaus} = \frac{N_{cor}^{-}/N^{-}}{N_{cor}^{+}/N^{+}} = \frac{189.2/205}{190.9/214} = 1.06$$

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Systematic uncertainties

- Charge correction method
 - Evaluated at the difference in C_{charge} between 4-Gaus and 2-Gaus methods ($\delta = 10.4\%$).
- Charge selection
 - The lower and upper bounds of charge selection cut ($0.4 < |Q \times E_T/p_T| < 1.8$) was varied by ± 0.3 .
 - The systematic uncertainty was taken from the largest deviation from the nominal value.

x _{low}	0.4	0.1	0.7	0.4	0.4	Largest	
x_{high}	1.8	1.8	1.8	1.5	2.1	Difference	
4-Gaus	0.96	0.88	1.12	0.89	0.97	0.16	Nominal
2-Gaus	1.06	1.09	1.06	1.04	1.04	0.03	

- QCD background description
 - Systematic uncertainty estimated by varying the upper r_{ESMD} limit for QCD background from 0.4 to 0.55 in steps of 0.01 (shape) and sp_{T,bal} upper limit from -4 GeV to 22 GeV in steps of 2 GeV (normalization).
 - The value was taken from the RMS of QCD contribution.





Results & Summary



- R_W in the endcap region with STAR Run 2017 dataset has been measured.
 - Evaluated at 25 GeV $< E_T < 50~GeV$ and $1 < \eta < 1.5$
 - Efficiency correction factor $\frac{\epsilon^-}{\epsilon^+} = 1.01$ was used.
 - Charge correction factor was calculated with the MC template method $\left(\frac{r^-}{r^+} = 0.96\right)$.
- Assigned systematics evaluates:
 - The difference between the two charge correction estimates (MC template vs. Log-likelihood)
 - The lower and upper limits of charge selection cut.
 - Description of the QCD background.
- Preliminary request for DIS2022



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• Caption: Signal and background signed- $p_{T,bal}$ distributions for positron candidates in the EEMC.



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• Caption: Signal and background signed- $p_{T,bal}$ distributions for electron candidates in the EEMC.







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 Caption: Total efficiencies of electroweak positrons and electrons plotted as a function of the leptonic pseudorapidity.









Caption: $Q \times E_T / p_T$ distributions from the STAR 2017 dataset. The black curve represents the 4-Gaus fit using the parameters obtained from fitting the MC distributions to a 2-Gaus function. The blue and red curves represent the estimated charge distributions for positron and electron candidates, respectively.









Caption: R_W for STAR 2017 dataset against leptonic pseudorapidity in comparison to the published measurement using STAR 2011, 2012, and 2013 datasets. The central values correspond to the mean value of η_{e} for that bin. The vertical bars represent the statistical uncertainty, whereas the height of the rectangles represents the systematic uncertainty for the respective data point. The measurement is compared to various theory frameworks with several PDF inputs.





• Caption: R_W for combined STAR 2011, 2012, 2013 and 2017 datasets against leptonic pseudorapidity. The central values correspond to the mean value of η_e for that bin. The vertical bars represent the statistical uncertainty, whereas the height of the rectangles represents the systematic uncertainty for the respective data point. The measurement is compared to various theory frameworks with several PDF inputs.













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Back up



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